











#### LM4040A10, LM4040A20

SLOS456M - JANUARY 2005 - REVISED JANUARY 2015

# LM4040xxx Precision Micropower Shunt Voltage Reference

#### **Features**

- Fixed Output Voltages of 2.048 V, 2.5 V, 3 V, 4.096 V, 5 V, 8.192 V, and 10 V
- Tight Output Tolerances and Low Temperature Coefficient
  - Max 0.1%, 100 ppm/°C A Grade
  - Max 0.2%, 100 ppm/°C B Grade
  - Max 0.5%, 100 ppm/°C C Grade
  - Max 1.0%, 150 ppm/°C D Grade
- Low Output Noise: 35 µV<sub>RMS</sub> Typ
- Wide Operating Current Range: 45 µA Typ to 15
- Stable With All Capacitive Loads: No Output Capacitor Required
- Available in Extended Temperature Range: -40°C to 125°C

#### 2 Applications

- **Data-Acquisition Systems**
- Power Supplies and Power-Supply Monitors
- Instrumentation and Test Equipment
- **Process Controls**
- **Precision Audio**
- Automotive Electronics
- **Energy Management**
- **Battery-Powered Equipment**

## 3 Description

The LM4040 series of shunt voltage references are versatile, easy-to-use references that cater to a vast array of applications. The 2-pin fixed-output device requires no external capacitors for operation and is stable with all capacitive loads. Additionally, the reference offers low dynamic impedance, low noise, and low temperature coefficient to ensure a stable output voltage over a wide range of operating currents and temperatures. The LM4040 uses fuse and Zener-zap reverse breakdown voltage trim during wafer sort to offer four output voltage tolerances, ranging from 0.1% (max) for the A grade to 1% (max) for the D grade. Thus, a great deal of flexibility is offered to designers in choosing the best cost-toperformance ratio for their applications.

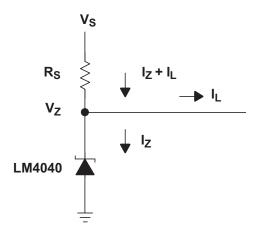
Packaged in space-saving SC-70 and SOT-23-3 packages and requiring a minimum current of 45 µA (typ), the LM4040 also is ideal for portable applications. The LM4040xl is characterized for operation over an ambient temperature range of -40°C to 85°C. The LM4040xQ is characterized for operation over an ambient temperature range of –40°C to 125°C.

## Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE (PIN)	BODY SIZE (NOM)			
LM4040voor	SOT-23 (3)	2.92 mm × 1.30 mm			
LM4040xxx	SC70 (6)	2.00 mm × 1.25 mm			

(1) For all available packages, see the orderable addendum at the end of the data sheet.

# **Simplified Schematic**





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## 5 Revision History

#### Changes from Revision L (January 2009) to Revision M

Page

- Added Applications, Device Information table, Pin Functions table, ESD Ratings table, Thermal Information table,
  Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply
  Recommendations section, Layout section, Device and Documentation Support section, and Mechanical,
  Packaging, and Orderable Information section.

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Table 1. Device Comparison Table (1)

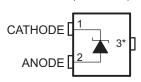
T <sub>A</sub>	DEVICE GRADE	V <sub>KA</sub>	ORDERABLE PART NUMBER
		2.048 V	LM4040A20I
	A grade:	2.5 V	LM4040A25I
	0.1% initial accuracy	3 V	LM4040A30I
	and	4.096 V	LM4040A41I
	100 ppm/°C temperature	5 V	LM4040A50I
	coefficient	8.192 V	LM4040A82I
-40°C to 85°C		10 V	LM4040A10I
-40°C to 85°C		2.048 V	LM4040B20I
	B grade:	2.5 V	LM4040B25I
	0.2% initial accuracy	3 V	LM4040B30I
	and	4.096 V	LM4040B41I
	100 ppm/°C temperature	5 V	LM4040B50I
	coefficient	8.192 V	LM4040B82I
		10 V	LM4040B10I
		2.048 V	LM4040C20I
	C grade: 0.5% initial accuracy	2.5 V	LM4040C25I
		3 V	LM4040C30I
-40°C to 85°C	and	4.096 V	LM4040C41I
	100 ppm/°C temperature coefficient	5 V	LM4040C50I
		8.192 V	LM4040C82I
		10 V	LM4040C10I
		2.048 V	LM4040D20I
	D grade:	2.5 V	LM4040D25I
	1.0% initial accuracy	3 V	LM4040D30I
–40°C to 85°C	and	4.096 V	LM4040D41I
	150 ppm/°C temperature	5 V	LM4040D50I
	coefficient	8.192 V	LM4040D82I
		10 V	LM4040D10I
	C grade:	2.048 V	LM4040C20Q
	0.5% initial accuracy	2.5 V	LM4040C25Q
	and	3 V	LM4040C30Q
4000 / 40500	100 ppm/°C temperature coefficient	5 V	LM4040C50Q
–40°C to 125°C	D grade:	2.048 V	LM4040D20Q
	1.0% initial accuracy	2.5 V	LM4040D25Q
	and	3 V	LM4040D30Q
	150 ppm/°C temperature coefficient	5 V	LM4040D50Q

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

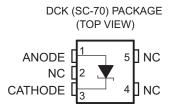


## 6 Pin Configuration and Functions

DBZ (SOT-23) PACKAGE (TOP VIEW)



\* Pin 3 is attached to substrate and must be connected to ANODE or left open.



NC - No internal connection

#### **Pin Functions**

	PIN		TVDE	DESCRIPTION
NAME	DBZ	DCK	TYPE	DESCRIPTION
CATHODE	1	3	I/O	Shunt Current/Voltage input
ANODE	2	1	0	Common pin, normally connected to ground
NC	_	2, 4, 5	I	No Internal Connection
*	3	_	I	Substrate Connection



## 7 Specifications

## 7.1 Absolute Maximum Ratings

over free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		MIN	MAX	UNIT
$I_Z$	Continuous cathode current	-10	25	mA
$T_{J}$	Operating virtual junction temperature		150	°C
T <sub>stg</sub>	Storage temperature range	-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions on timplied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 7.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins (1)	±2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±1000	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

#### 7.3 Recommended Operating Conditions

			MIN	MAX	UNIT
$I_Z$	Cathode current		(1)	15	mA
_	Free cir temperature	LM4040xxxI	-40	85	°C
IA	Free-air temperature	LM4040xxxQ	-40	125	°C

<sup>(1)</sup> See parametric tables

## 7.4 Thermal Information

		LM40	40xxx	
	THERMAL METRIC <sup>(1)</sup>	DBZ DCK		UNIT
		3 PINS	5 PINS	
R <sub>0JA</sub> Junction	n-to-ambient thermal resistance	206	252	°C/W

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report (SPRA953).

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## 7.5 LM4040A20I, LM4040B20I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040A2	Ol	LN	14040B2	01	LINUT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		2.048			2.048		V
۸۱/_	AV <sub>Z</sub> Reverse breakdown voltage tolerance	I <sub>7</sub> = 100 μA	25°C	-2		2	-4.1		4.1	mV
ΔvZ		12 = 100 μΑ	Full range	-15		15	-17		17	IIIV
1-	Minimum cathode current		25°C		45	75		45	75	μA
I <sub>Z,min</sub>	min willillium cathode current,		Full range			80			80	μΑ
		I <sub>Z</sub> = 10 mA	25°C		±20			±20		
<b>a</b>	Average temperature coefficient	I <sub>Z</sub> = 1 mA	25°C		±15			±15		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage		Full range			±100			±100	ррпі/ С
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.3	0.8		0.3	0.8	mV
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage change with cathode current		Full range			1			1	
$\Delta I_Z$	change with cathode current	4 45 4	25°C		2.5	6		2.5	6	
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			8			8	
Z <sub>Z</sub>	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.3	0.8		0.3	0.8	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
V <sub>HYST</sub>	Thermal hysteresis <sup>(1)</sup>	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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## 7.6 LM4040C20I, LM4040D20I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$ °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	_	LM	4040C2	DI	LN	14040D2	01	
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
Vz	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		2.048			2.048		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-10		10	-20		20	mV
Δν2	tolerance	12 = 100 μΑ	Full range	-23		23	-40		40	IIIV
I	Minimum cathodo current		25°C		45	75		45	75	μA
$I_{Z,min}$	Minimum cathode current		Full range			80			80	μΑ
		$I_Z = 10 \text{ mA}$	25°C		±20			±20		
~	Average temperature coefficient of reverse breakdown voltage	I <sub>Z</sub> = 1 mA	25°C		±15			±15		ppm/°C
$\alpha_{VZ}$			Full range			±100			±150	ррпі, С
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.3	8.0		0.3	1	mV
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage		Full range			1			1.2	
$\Delta I_Z$	change with cathode current change	4 4 1 45 4	25°C		2.5	6		2.5	8	
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			8			10	
Z <sub>Z</sub>	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.3	0.9		0.3	1.1	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).



## 7.7 LM4040C20Q, LM4040D20Q Electrical Characteristics

at extended temperature range, full-range  $T_A = -40$ °C to 125°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	_	LM4	4040C20	Q	LM4040D20Q			UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
Vz	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		2.048			2.048		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-10		10	-20		20	mV
ΔνΖ	tolerance	12 = 100 μΑ	Full range	-30		30	-50		50	IIIV
I	Minimum cathode current		25°C		45	75		45	75	μA
$I_{Z,min}$	Minimum catnode current		Full range			80			80	μΛ
		I <sub>Z</sub> = 10 mA	25°C		±20			±20		
<b>a</b>	Average temperature coefficient	I <sub>7</sub> = 1 mA	25°C		±15			±15		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	IZ = 1 IIIA	Full range			±100			±150	ррпі, О
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.3	8.0		0.3	1	mV
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage change with cathode current		Full range			1			1.2	
$\Delta I_Z$	change with cathode current	1 mA < I <sub>Z</sub> < 15 mA	25°C		2.5	6		2.5	8	
		T IIIA < IZ < 13 IIIA	Full range			8			10	
Z <sub>Z</sub>	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.3	0.9		0.3	1.1	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
V <sub>HYST</sub>	Thermal hysteresis (1)	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).



## 7.8 LM4040A25I, LM4040B25I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40^{\circ}C$  to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	_	LM	4040A2	5I	LM4040B25I			LINUT	
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		2.5			2.5		V	
$\Delta V_Z$	Reverse breakdown voltage		25°C	-2.5		2.5	<b>–</b> 5		5	mV	
ΔVZ	tolerance		Full range	-19		19	-21		21	IIIV	
I	Minimum cathode current		25°C		45	75		45	75	μA	
I <sub>Z,min</sub>	i,min willilliam cathode carrent	iviinimum catnode current		Full range			80			80	μΛ
		I <sub>Z</sub> = 10 mA	25°C		±20			±20			
~	Average temperature coefficient	I <sub>Z</sub> = 1 mA	25°C		±15			±15		ppm/°C	
$\alpha_{VZ}$	of reverse breakdown voltage		Full range			±100			±100	ррпі, С	
		I <sub>Z</sub> = 100 μA	25°C		±15			±15			
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.3	0.8		0.3	0.8	mV	
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage change with cathode current		Full range			1			1		
$\Delta I_Z$	change with cathode current	4 45 4	25°C		2.5	6		2.5	6		
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			8			8		
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.3	0.8		0.3	0.8	Ω	
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		$\mu V_{RMS}$	
	Long-term stability of reverse breakdown voltage	t = 1000  h, $T_A = 25^{\circ}\text{C} \pm 0.1^{\circ}\text{C},$ $I_Z = 100 \mu\text{A}$			120			120		ppm	
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_	

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).



## 7.9 LM4040C25I, LM4040D25I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040C2	5I	LM	4040D2	51	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		2.5			2.5		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-12		12	-25		25	mV
ΔvZ	tolerance	12 = 100 μΑ	Full range	-29		29	-49		49	IIIV
I	Minimum cathode current		25°C		45	75		45	75	μA
I <sub>Z,min</sub>	Willimum cathode current		Full range			80			80	μΑ
		$I_Z = 10 \text{ mA}$	25°C		±20			±20		
~	Average temperature coefficient	l - 1 mΛ	25°C		±15			±15		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±150	ppin/ C
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.3	8.0		0.3	1	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			1			1.2	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		2.5	6		2.5	8	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			8			10	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.3	0.9		0.3	1.1	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		$\mu V_{RMS}$
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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## 7.10 LM4040C25Q, LM4040D25Q Electrical Characteristics

at extended temperature range, full-range  $T_A = -40$  °C to 125 °C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM4	4040C25	iQ	LM4	4040D25	5Q	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		2.5			2.5		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-12		12	-25		25	mV
ΔvZ	tolerance	12 = 100 μΑ	Full range	-38		38	-63		63	IIIV
I	Minimum cathode current		25°C		45	75		45	75	μA
$I_{Z,min}$	Willimum Cathode Current		Full range			80			80	μΑ
		I <sub>Z</sub> = 10 mA	25°C		±20			±20		
~	Average temperature coefficient		25°C		±15			±15		nnm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±150	ppm/°C
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.3	0.8		0.3	1	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			1			1.2	mV
$\frac{Z}{\Delta I_Z}$	change with cathode current	1 m \ .   . 15 m \	25°C		2.5	6		2.5	8	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			8			10	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.3	0.9		0.3	1.1	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis <sup>(1)</sup>	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).



## 7.11 LM4040A30I, LM4040B30I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040A3	OI	LM	4040B3	01	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		3			3		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-3		3	-6		6	mV
ΔvZ	tolerance	12 = 100 μΑ	Full range	-22		22	-26		26	IIIV
I	Minimum cathode current		25°C		47	77		47	77	
I <sub>Z,min</sub>	Willimum Cathode Current		Full range			82			82	μA
		$I_Z = 10 \text{ mA}$	25°C		±20			±20		
~	Average temperature coefficient	l - 1 mΛ	25°C		±15			±15		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±100	ppin/ C
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.6	0.8		0.6	0.8	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			1.1			1.1	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		2.7	6		2.7	6	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			9			9	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.4	0.9		0.4	0.9	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		$\mu V_{RMS}$
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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Product Folder Links: LM4040A10 LM4040A20



## 7.12 LM4040C30I, LM4040D30I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040C3	OI	LM	4040D3	01	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		3			3		V
۸۱/_	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-15		15	-30		30	mV
$\Delta V_Z$	tolerance	12 = 100 μΑ	Full range	-34		34	-59		59	IIIV
I	Minimum cathode current		25°C		45	77		45	77	^
I <sub>Z,min</sub>	Willimum cathode current		Full range			82			82	μA
		$I_Z = 10 \text{ mA}$	25°C		±20			±20		
~	Average temperature coefficient	l - 1 mΛ	25°C		±15			±15		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±150	ppiii/ C
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.4	0.8		1.4	1	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			1.1			1.3	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		2.7	6		2.7	8	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			9			11	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.4	0.9		0.4	1.2	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

Product Folder Links: LM4040A10 LM4040A20



## 7.13 LM4040C30Q, LM4040D30Q Electrical Characteristics

at extended temperature range, full-range  $T_A = -40$ °C to 125°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	_	LM4	1040C30	Q	LM4	1040D30	Q	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
Vz	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		3			3		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-15		15	-30		30	mV
ΔνΖ	tolerance	12 = 100 μΑ	Full range	-45		45	<del>-</del> 75		75	IIIV
I	Minimum cathode current		25°C		47	77		47	77	μA
$I_{Z,min}$	Willimum Cathode Current		Full range			82			82	μΑ
		$I_Z = 10 \text{ mA}$	25°C		±20			±20		
~	Average temperature coefficient	I <sub>7</sub> = 1 mA	25°C		±15			±15		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	IZ = 1 IIIA	Full range			±100			±150	ppin/ C
		I <sub>Z</sub> = 100 μA	25°C		±15			±15		
		l -1 -1 mΛ	25°C		0.4	0.8		0.4	1.1	
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage	$I_{Z,min} < I_Z < 1 \text{ mA}$	Full range			1.1			1.3	mV
$\Delta I_Z$	change with cathode current change	1 m \ .   . 15 m \	25°C		2.7	6		2.7	8	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			9			11	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.4	0.9		0.4	1.2	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		35			35		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
V <sub>HYST</sub>	Thermal hysteresis (1)	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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## 7.14 LM4040A41I, LM4040B41I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$ °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040A4	11	LN	14040B4	11	LINUT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		4.096			4.096		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-4.1		4.1	-8.2		8.2	mV
ΔVZ	tolerance	12 = 100 μΑ	Full range	-31		31	-35		35	IIIV
1	Minimum cathode current		25°C		50	83		50	83	μA
I <sub>Z,min</sub>	Willimum Cathode Current		Full range			88			88	μΑ
		I <sub>Z</sub> = 10 mA	25°C		±30			±30		
<b>a</b>	Average temperature coefficient	I <sub>7</sub> = 1 mA	25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	IZ = I IIIA	Full range			±100			±100	ppiii/ C
		I <sub>Z</sub> = 100 μA	25°C		±20			±20		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.5	0.9		0.5	0.9	
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			1.2			1.2	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		3	7		3	7	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			10			10	
Z <sub>Z</sub>	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.5	1		0.5	1	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		80			80		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
V <sub>HYST</sub>	Thermal hysteresis <sup>(1)</sup>	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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Product Folder Links: LM4040A10 LM4040A20



## 7.15 LM4040C41I, LM4040D41I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040C4	11	LN	14040D4	11	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		4.096			4.096		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-20		20	-41		41	mV
ΔvZ	tolerance	12 = 100 μΑ	Full range	-47		47	-81		81	IIIV
1	Minimum cathode current		25°C		50	83		50	83	μA
$I_{Z,min}$	Willimum cathode current		Full range			88			88	μΑ
		I <sub>Z</sub> = 10 mA	25°C		±30			±30		
~	Average temperature coefficient		25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±150	ррпі/ С
		I <sub>Z</sub> = 100 μA	25°C		±20			±20		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.5	0.9		0.5	1.2	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			1.2			1.5	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		3	7		3	9	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			10			13	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.5	1		0.5	1.3	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		80			80		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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## 7.16 LM4040A50I, LM4040B50I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$ °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	_	LM	4040A5	OI	LM	4040B5	01	
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		5			5		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	<b>–</b> 5		5	-10		10	mV
ΔVZ	tolerance	12 = 100 μΑ	Full range	-38		38	-43		43	IIIV
I	Minimum cathode current		25°C		65	89		65	89	^
I <sub>Z,min</sub>	Willimum Cathode Current		Full range			95			95	μA
		$I_Z = 10 \text{ mA}$	25°C		±30			±30		
~	Average temperature coefficient	I <sub>7</sub> = 1 mA	25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	IZ = 1 IIIA	Full range			±100			±100	ppiii/ C
		I <sub>Z</sub> = 100 μA	25°C		±20			±20		
			25°C		0.5	1		0.5	1	
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage change with cathode current	$I_{Z,min} < I_Z < 1 \text{ mA}$	Full range			1.4			1.4	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		3.5	8		3.5	8	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			12			12	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.5	1.1		0.5	1.1	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		80			80		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000  h, $T_A = 25^{\circ}\text{C} \pm 0.1^{\circ}\text{C},$ $I_Z = 100 \mu\text{A}$			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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## 7.17 LM4040C50I, LM4040D50I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040C5	Ol	LM	4040D5	Ol	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		5			5		V
۸۱/_	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-25		25	-50		50	mV
$\Delta V_Z$	tolerance	12 = 100 μΑ	Full range	-58		58	-99		99	IIIV
1	Minimum cathode current		25°C		65	89		65	89	
$I_{Z,min}$	Willimum Cathode Current		Full range			95			95	μA
		I <sub>Z</sub> = 10 mA	25°C		±30			±30		
~	Average temperature coefficient		25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±150	ppin/ C
		I <sub>Z</sub> = 100 μA	25°C		±20			±20		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.5	1		0.5	1.3	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			1.4			1.8	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		3.5	8		3.5	10	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			12			15	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.5	1.1		0.5	1.5	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		80			80		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
V <sub>HYST</sub>	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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## 7.18 LM4040C50Q, LM4040D50Q Electrical Characteristics

at extended temperature range, full-range  $T_A = -40$ °C to 125°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	_	LM4	1040C50	Q	LM4	040D50	Q	LINIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 100 μA	25°C		5			5		>
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 100 μA	25°C	-25		25	-50		50	mV
Δν2	tolerance	12 = 100 μΑ	Full range	-75		75	-125		125	IIIV
1	Minimum cathode current		25°C		65	89		65	89	μA
$I_{Z,min}$	willimani catriode current		Full range			95			95	μΑ
		I <sub>Z</sub> = 10 mA	25°C		±30			±30		
~	Average temperature coefficient	I <sub>7</sub> = 1 mA	25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	IZ = 1 IIIA	Full range			±100			±150	ррпі/ С
		I <sub>Z</sub> = 100 μA	25°C		±20			±20		
		l -1 -1 mΛ	25°C		0.5	1		0.5	1	
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage	$I_{Z,min} < I_Z < 1 \text{ mA}$	Full range			1.4			1.8	mV
$\Delta I_Z$	change with cathode current change	1 m \ . 1 . 15 m \	25°C		3.5	8		3.5	8	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			12			12	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.5	1.1		0.5	1.1	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 100 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		80			80		$\mu V_{RMS}$
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 100 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).



## 7.19 LM4040A82I, LM4040B82I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	14040A8	21	LN	14040B8	21	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 150 μA	25°C		8.192			8.192		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 150 μA	25°C	-8.2		8.2	-16		16	mV
ΔVZ	tolerance	12 = 150 μΑ	Full range	-61		61	-70		70	IIIV
1	Minimum cathode current		25°C		67	106		67	106	
$I_{Z,min}$	Willimum cathode current		Full range			110			110	μA
		$I_Z = 10 \text{ mA}$	25°C		±40			±40		
~	Average temperature coefficient	l - 1 mΛ	25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±100	ppin/ C
		I <sub>Z</sub> = 150 μA	25°C		±20			±20		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		0.6	1.3		0.6	1.6	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			2.5			2.5	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		7	10		7	10	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			18			18	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.6	1.5		0.6	1.5	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 150 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		130			130		$\mu V_{RMS}$
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 150 μA			120			120		ppm
V <sub>HYST</sub>	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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Product Folder Links: LM4040A10 LM4040A20



## 7.20 LM4040C82I, LM4040D82I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$ °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	14040C8	21	LN	14040D8	21	LINUT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
$V_{Z}$	Reverse breakdown voltage	I <sub>Z</sub> = 150 μA	25°C		8.192			8.192		V
۸۱/	Reverse breakdown voltage	1 – 150 μΔ	25°C	-41		41	-82		82	mV
$\Delta V_Z$	tolerance	$I_Z = 150 \mu A$	Full range	-94		94	-162		162	IIIV
	Minimum cathode current		25°C		67	106		67	111	
$I_{Z,min}$	Minimum cathode current		Full range			110			115	μA
		I <sub>Z</sub> = 10 mA	25°C		±40			±40		
_	Average temperature coefficient	1 4 0	25°C		±20			±20		/00
$\alpha_{VZ}$	of reverse breakdown voltage	$I_Z = 1 \text{ mA}$	Full range			±100			±150	ppm/°C
		I <sub>Z</sub> = 150 μA	25°C		±20			±20		
		Ι	25°C		0.6	1.3		0.6	1.7	
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage	$I_{Z,min} < I_Z < 1 \text{ mA}$	Full range			2.5			3	mV
$\Delta I_Z$	change with cathode current change	4 4 45 4	25°C		7	10		7	15	IIIV
	· ·	1 mA < I <sub>Z</sub> < 15 mA	Full range			18			24	
Z <sub>Z</sub>	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.6	1.5		0.6	1.9	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 150 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		130			130		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 150 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis <sup>(1)</sup>	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).



## 7.21 LM4040A10I, LM4040B10I Electrical Characteristics

at industrial temperature range, full-range  $T_A = -40$  °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	-	LM	4040A1	OI	LM	4040B1	01	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 150 μA	25°C		10			10		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 150 μA	25°C	-10		10	-20		20	mV
ΔVZ	tolerance	12 = 150 μΑ	Full range	-75		75	-85		85	IIIV
I	Minimum cathode current		25°C		75	120		75	120	
I <sub>Z,min</sub>	Willimum cathode current		Full range			125			125	μA
		I <sub>Z</sub> = 10 mA	25°C		±40			±40		
~	Average temperature coefficient	I <sub>7</sub> = 1 mA	25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	IZ = I IIIA	Full range			±100			±100	ppin/ C
		I <sub>Z</sub> = 150 μA	25°C		±20			±20		
		$I_{Z,min} < I_Z < 1 \text{ mA}$	25°C		8.0	1.5		8.0	1.5	
$\Delta V_Z$	Reverse breakdown voltage change with cathode current	IZ,min < IZ < I IIIA	Full range			3.5			3.5	mV
$\Delta I_Z$	change with cathode current	1 m \ .   . 15 m \	25°C		8	14		8	14	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			24			24	
$Z_Z$	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.7	1.7		0.7	1.7	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 150 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		180			180		$\mu V_{RMS}$
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 150 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40^{\circ}C$ to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

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Product Folder Links: LM4040A10 LM4040A20



## 7.22 LM4040C10I, LM4040D10I Electrical Characteristics

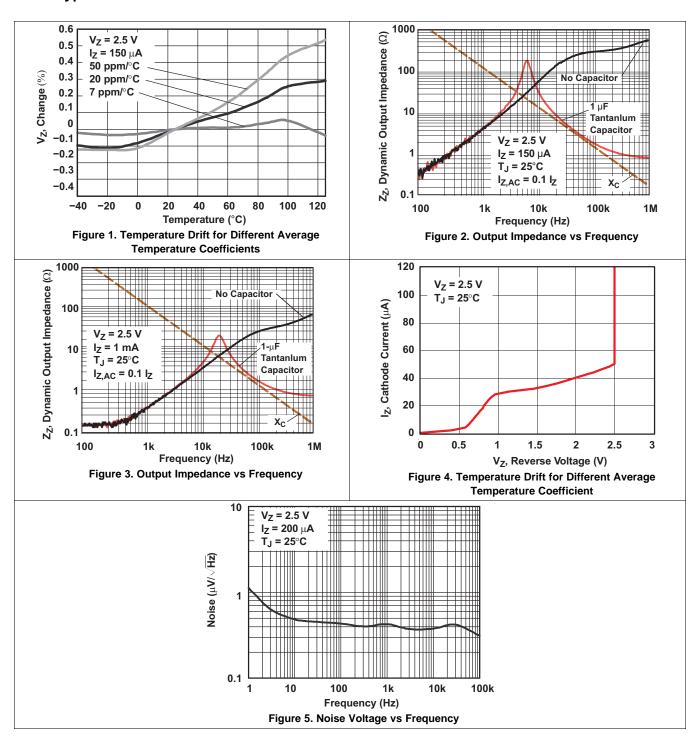
at industrial temperature range, full-range  $T_A = -40$ °C to 85°C (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	_	LM	4040C1	DI	LM	4040D1	01	UNIT
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
$V_Z$	Reverse breakdown voltage	I <sub>Z</sub> = 150 μA	25°C		10			10		V
$\Delta V_Z$	Reverse breakdown voltage	I <sub>7</sub> = 150 μA	25°C	-50		50	-100		100	mV
Δν2	tolerance	12 = 150 μΑ	Full range	-115		115	-198		198	IIIV
I	Minimum cathode current		25°C		75	120		75	130	μA
$I_{Z,min}$	Willimum Cathode Current		Full range			125			135	μΑ
		I <sub>Z</sub> = 10 mA	25°C		±40			±40		
~	Average temperature coefficient	I <sub>7</sub> = 1 mA	25°C		±20			±20		ppm/°C
$\alpha_{VZ}$	of reverse breakdown voltage	IZ = I IIIA	Full range			±100			±150	ppiii/ C
		I <sub>Z</sub> = 150 μA	25°C		±20			±20		
		l -1 -1 mΛ	25°C		0.8	1.5		0.8	2	
$\frac{\Delta V_Z}{\Delta I_Z}$	Reverse breakdown voltage	$I_{Z,min} < I_Z < 1 \text{ mA}$	Full range			3.5			4	mV
$\Delta I_Z$	change with cathode current change	1 m \ . 1 . 15 m \	25°C		8	14		8	18	IIIV
	-	1 mA < I <sub>Z</sub> < 15 mA	Full range			24			29	
Z <sub>Z</sub>	Reverse dynamic impedance	$I_Z = 1 \text{ mA, f} = 120 \text{ Hz,}$ $I_{AC} = 0.1 I_Z$	25°C		0.7	1.7		0.7	2.3	Ω
e <sub>N</sub>	Wideband noise	I <sub>Z</sub> = 150 μA, 10 Hz ≤ f ≤ 10 kHz	25°C		180			180		μV <sub>RMS</sub>
	Long-term stability of reverse breakdown voltage	t = 1000 h, T <sub>A</sub> = 25°C ± 0.1°C, I <sub>Z</sub> = 150 μA			120			120		ppm
$V_{HYST}$	Thermal hysteresis (1)	$\Delta T_A = -40$ °C to 125°C			0.08%			0.08%		_

<sup>(1)</sup> Thermal hysteresis is defined as  $V_{Z,25^{\circ}C}$  (after cycling to  $-40^{\circ}C$ ) –  $V_{Z,25^{\circ}C}$  (after cycling to  $125^{\circ}C$ ).

# TEXAS INSTRUMENTS

## 7.23 Typical Characteristics





## 8 Detailed Description

#### 8.1 Overview

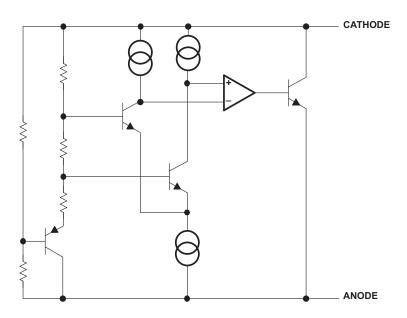
The LM4040 is a precision micro-power curvature-corrected bandgap shunt voltage reference. The LM4040 has been designed for stable operation without the need of an external capacitor connected between the "+" pin and the "-" pin. If, however, a bypass capacitor is used, the LM4040 remains stable.

LM4040 offers several fixed reverse breakdown voltages: 2.048 V, 2.500 V, 3.000 V, 4.096 V, 5.000 V, 6.000, 8.192 V, and 10.000 V. The minimum operating current increases from 60  $\mu$ A for the LM4040-N-2.048 and LM4040-N-2.5 to 100  $\mu$ A for the 10.0-V LM4040. All versions have a maximum operating current of 15 mA.

Each reverse voltage options can be purchased with initial tolerances (at 25°C) of 0.1%, 0.2%, 0.5% and 1.0%. These reference options are denoted by A (0.1%), B (0.2%), C (0.5%) and D for (1.0%).

The LM4040xxxI devices are characterized for operation from -40°C to 85°C, and the LM4040xxxQ devices are characterized for operation from -40°C to 125°C.

## 8.2 Functional Block Diagram



#### 8.3 Feature Description

A temperature compensated band gap voltage reference controls high gain amplifier and shunt pass element to maintain a nearly constant voltage between cathode and anode. Regulation occurs after a minimum current is provided to power the voltage divider and amplifier. Internal frequency compensation provides a stable loop for all capacitor loads. Floating shunt design is useful for both positive and negative regulation applications.

#### 8.4 Device Functional Modes

## 8.4.1 Shunt Reference

LM4040x will operate in one mode, which is as a fixed voltage reference that cannot be adjusted. LM4040x does offer various Reverse Voltage options that have unique electrical characteristics detailed in the *Specifications* section.

In order for a proper Reverse Voltage to be developed, current must be sourced into the cathode of LM4040x. The minimum current needed for proper regulation is denoted in the *Specifications* section as I<sub>7 min</sub>.

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## 9 Applications and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

## 9.1 Application Information

LM4040xxx is a well known industry standard device used in several applications and end equipment where a reference is required. Below describes this device being used in a data acquisition system. Analog to Digital conversion systems are the most common applications to use LM4040x due to its low reference tolerance which allows high precision in these systems.

## 9.2 Typical Applications

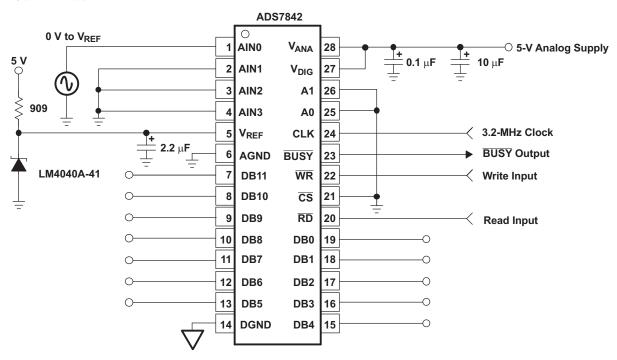


Figure 6. Data-Acquisition Circuit With LM4040x-41

#### 9.2.1 Design Requirements

For this design example, use the parameters listed in Table 2 as the input parameters.

**Table 2. Design Parameters** 

DESIGN PARAMETER	EXAMPLE VALUE
ADC FSR (Full Scale Range)	4.096
ADC Resolution	12 Bits
Supply Voltage	5 V
Cathode Current (lk)	100 μΑ

Product Folder Links: LM4040A10 LM4040A20



#### 9.2.2 Detailed Design Procedure

When using LM4040x as a comparator with reference, determine the following:

- Input voltage range
- Reference voltage accuracy
- Output logic input high and low level thresholds
- Current source resistance

#### 9.2.2.1 LM4040x Voltage and Accuracy Choice

When using LM4040x as a reference for an ADC, the ADC's FSR (Full Scale Range), Resolution and LSB must be determined. LSB can be determined by:

#### LSB=FSR/(2N-1)

With N being the resolution or Number of Bits. FSR and Resolution can be determined by the ADC's datasheet.

Vref can be determined by:

#### Vref=FSR+LSB

Though modern data converters use calibration techniques to compensate for any error introduced by a Vref's inaccuracy, it is best to use the highest accuracy available. This is due to errors in the calibration method that may allow some non-linearities introduced by the Vref's initial accuracy.

A good example is the LM4040x-41 that is designed to be a cost-effective voltage reference as required in 12-bit data-acquisition systems. For 12-bit systems operating from 5-V supplies (see Figure 6), the LM4040A-41 (4.096 V, 0.01%) only introduces 4 LSBs (4mV) of possible error in a system that consists of 4096 LSBs.

#### 9.2.2.2 Cathode and Load Currents

In a typical shunt-regulator configuration (see Figure 7), an external resistor,  $R_S$ , is connected between the supply and the cathode of the LM4040.  $R_S$  must be set properly, as it sets the total current available to supply the load ( $I_L$ ) and bias the LM4040 ( $I_Z$ ). In all cases,  $I_Z$  must stay within a specified range for proper operation of the reference. Taking into consideration one extreme in the variation of the load and supply voltage (maximum  $I_L$  and minimum  $V_S$ ),  $R_S$  must be small enough to supply the minimum  $I_Z$  required for operation of the regulator, as given by data-sheet parameters. At the other extreme, maximum  $V_S$  and minimum  $I_L$ ,  $R_S$  must be large enough to limit  $I_Z$  to less than its maximum-rated value of 15 mA.

R<sub>S</sub> is calculated according to Equation 1:

$$R_{S} = \frac{\left(V_{S} - V_{Z}\right)}{\left(I_{L} + I_{Z}\right)} \tag{1}$$

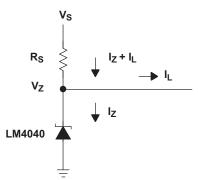


Figure 7. Shunt Regulator

#### 9.2.2.3 Output Capacitor

The LM4040 does not require an output capacitor across cathode and anode for stability. However, if an output bypass capacitor is desired, the LM4040 is designed to be stable with all capacitive loads.

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#### 9.2.2.4 SOT-23 Connections

There is a parasitic Schottky diode connected between pins 2 and 3 of the SOT-23 packaged device. Thus, pin 3 of the SOT-23 package must be left floating or connected to pin 2.

#### 9.2.2.5 Start-Up Characteristics

In any data conversion system, start-up characteristics are important, as to determine when it is safe begin conversion based upon a steady and settled reference value. As shown in Figure 9 it is best to allow for >20µs from supply start-up to begin conversion.

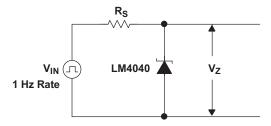
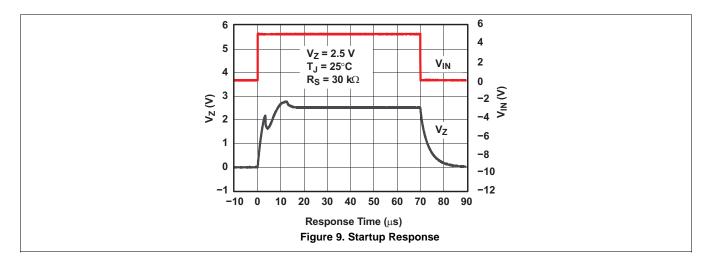


Figure 8. Test Circuit

#### 9.2.3 Application Curves



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## 10 Power Supply Recommendations

In order to not exceed the maximum cathode current, be sure that the supply voltage is current limited.

For applications shunting high currents (15 mA max), pay attention to the cathode and anode trace lengths, adjusting the width of the traces to have the proper current density.

#### 11 Layout

## 11.1 Layout Guidelines

Figure 10 shows an example of a PCB layout of LM4040XXXDBZ. Some key V<sub>ref</sub> noise considerations are:

- Connect a low-ESR, 0.1-µF (C<sub>I</sub>) ceramic bypass capacitor on the cathode pin node.
- Decouple other active devices in the system per the device specifications.
- Using a solid ground plane helps distribute heat and reduces electromagnetic interference (EMI) noise pickup.
- Place the external components as close to the device as possible. This configuration prevents parasitic errors (such as the Seebeck effect) from occurring.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible and only make perpendicular crossings when absolutely necessary.

#### 11.2 Layout Example

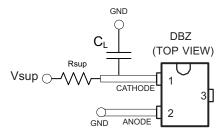


Figure 10. DBZ Layout example



## 12 Device and Documentation Support

#### 12.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 3. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
LM4040A10	Click here	Click here	Click here	Click here	Click here
LM4040A20	Click here	Click here	Click here	Click here	Click here

#### 12.2 Trademarks

All trademarks are the property of their respective owners.

## 12.3 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### 12.4 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.





7-Dec-2016

## **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LM4040A10IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NQ3 ~ 4NQU)	Samples
LM4040A10IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NQ3 ~ 4NQU)	Samples
LM4040A10IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NQ3 ~ 4NQU)	Samples
LM4040A10IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PHU	Samples
LM4040A10ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040A10ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040A20IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MC3 ~ 4MCU)	Samples
LM4040A20IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MC3 ~ 4MCU)	Samples
LM4040A20IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MC3 ~ 4MCU)	Samples
LM4040A20IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MC3 ~ 4MCU)	Samples
LM4040A20IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MSU	Samples
LM4040A20IDCKRE4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MSU	Samples
LM4040A25IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NG3 ~ 4NGU)	Samples
LM4040A25IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NG3 ~ 4NGU)	Samples
LM4040A25IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NG3 ~ 4NGU)	Samples
LM4040A25IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P2U	Samples
LM4040A25ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040A25ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040A30IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M63 ~ 4M6U)	Samples





Orderable Device	Status	Package Type	Package	Pins	_	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
LM4040A30IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M63 ~ 4M6U)	Samples
LM4040A30IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M63 ~ 4M6U)	Samples
LM4040A30IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M63 ~ 4M6U)	Samples
LM4040A30IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P9U	Samples
LM4040A30IDCKRE4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P9U	Samples
LM4040A30IDCKT	PREVIEW	SC70	DCK	5	250	TBD	Call TI	Call TI	-40 to 85		
LM4040A30ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040A30ILPM	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040A30ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040A41IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M23 ~ 4M2U)	Samples
LM4040A41IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M23 ~ 4M2U)	Samples
LM4040A41IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M23 ~ 4M2U)	Samples
LM4040A41IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M23 ~ 4M2U)	Samples
LM4040A41IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P4U	Samples
LM4040A41ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040A41ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040A50IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NA3 ~ 4NAU)	Samples
LM4040A50IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NA3 ~ 4NAU)	Samples
LM4040A50IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NA3 ~ 4NAU)	Samples
LM4040A50IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	N5U	Samples





Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LM4040A50IDCKRG4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	N5U	Samples
LM4040A50ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040A82IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NL3 ~ 4NLU)	Samples
LM4040A82IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NL3 ~ 4NLU)	Samples
LM4040A82IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NL3 ~ 4NLU)	Samples
LM4040A82IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PDU	Samples
LM4040B10IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NR3 ~ 4NRU)	Samples
LM4040B10IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NR3 ~ 4NRU)	Samples
LM4040B10IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NR3 ~ 4NRU)	Samples
LM4040B10IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PJU	Samples
LM4040B10ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040B10ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040B20IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MD3 ~ 4MDU)	Samples
LM4040B20IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MD3 ~ 4MDU)	Samples
LM4040B20IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MD3 ~ 4MDU)	Samples
LM4040B20IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MD3 ~ 4MDU)	Samples
LM4040B20IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(MTS ~ MTU)	Samples
LM4040B25IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NH3 ~ 4NHU)	Samples
LM4040B25IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NH3 ~ 4NHU)	Samples





Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LM4040B25IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NH3 ~ 4NHU)	Samples
LM4040B25IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NH3 ~ 4NHU)	Samples
LM4040B25IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P3U	Samples
LM4040B25IDCKRG4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P3U	Samples
LM4040B25ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040B25ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040B30IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M73 ~ 4M7U)	Sample
LM4040B30IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M73 ~ 4M7U)	Sample
LM4040B30IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M73 ~ 4M7U)	Sample
LM4040B30IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PAU	Sample
LM4040B30IDCKRG4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PAU	Sample
LM4040B30IDCKT	PREVIEW	SC70	DCK	5	250	TBD	Call TI	Call TI	-40 to 85		
LM4040B30ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040B30ILPM	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040B30ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040B41IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M33 ~ 4M3U)	Sample
LM4040B41IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M33 ~ 4M3U)	Sample
LM4040B41IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M33 ~ 4M3U)	Sample
LM4040B41IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P5U	Sample
LM4040B41ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040B41ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85	<u> </u>	





Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Sample
LM4040B50IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NB3 ~ 4NBU)	Sample
LM4040B50IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NB3 ~ 4NBU)	Sample
LM4040B50IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NB3 ~ 4NBU)	Sample
LM4040B50IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MXU	Sampl
LM4040B50ILP	PREVIEW	TO-92	LP	3	1000	TBD	Call TI	Call TI	-40 to 85		
LM4040B50ILPR	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040B82IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NM3 ~ 4NMU)	Sampl
LM4040C10IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NS3 ~ 4NSU)	Samp
LM4040C10IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NS3 ~ 4NSU)	Samp
LM4040C10IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NS3 ~ 4NSU)	Samp
LM4040C10IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PKU	Sampl
LM4040C10ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC10I	Samp
LM4040C10ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC10I	Samp
LM4040C10ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC10I	Samp
LM4040C10ILPRE3	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC10I	Samp
LM4040C20IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MQ3 ~ 4MQU)	Samp
LM4040C20IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MQ3 ~ 4MQU)	Samp
LM4040C20IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MQ3 ~ 4MQU)	Samp
LM4040C20IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MVU	Samp



Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Sample
LM4040C20ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC20I	Sample
LM4040C20ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC20I	Sample
LM4040C20ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC20I	Sample
LM4040C20QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MW3 ~ 4MWU)	Sample
LM4040C20QDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MW3 ~ 4MWU)	Sample
LM4040C20QDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MW3 ~ 4MWU)	Sample
LM4040C20QDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MW3 ~ 4MWU)	Sample
LM4040C25IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MU3 ~ 4MUU)	Sample
LM4040C25IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MU3 ~ 4MUU)	Sample
LM4040C25IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MU3 ~ 4MUU)	Sample
LM4040C25IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MU3 ~ 4MUU)	Sample
LM4040C25IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MUU	Sample
LM4040C25IDCKT	ACTIVE	SC70	DCK	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MUU	Sample
LM4040C25IDCKTE4	ACTIVE	SC70	DCK	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MUU	Sample
LM4040C25IDCKTG4	ACTIVE	SC70	DCK	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MUU	Sample
LM4040C25ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC25I	Sample
LM4040C25ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC25I	Sample
LM4040C25ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC25I	Sample





Orderable Device	Status	Package Type	_	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Sample
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
LM4040C25ILPRE3	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC25I	Sample
LM4040C25QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MA3 ~ 4MAU)	Sample
LM4040C25QDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MA3 ~ 4MAU)	Sample
LM4040C25QDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MA3 ~ 4MAU)	Sample
LM4040C25QDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MA3 ~ 4MAU)	Sample
LM4040C30IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M83 ~ 4M8U)	Sample
LM4040C30IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M83 ~ 4M8U)	Sample
LM4040C30IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M83 ~ 4M8U)	Sample
LM4040C30IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M83 ~ 4M8U)	Sample
LM4040C30IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PBU	Sample
LM4040C30IDCKT	PREVIEW	SC70	DCK	5	250	TBD	Call TI	Call TI	-40 to 85		
LM4040C30ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC30I	Sample
LM4040C30ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC30I	Sample
LM4040C30ILPM	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040C30ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC30I	Sampl
LM4040C30QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NJ3 ~ 4NJU)	Sample
LM4040C30QDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM -40 to 125		(4NJ3 ~ 4NJU)	Sampl
LM4040C41IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M43 ~ 4M4U)	Sampl
LM4040C41IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M43 ~ 4M4U)	Sampl





Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Sample
LM4040C41IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M43 ~ 4M4U)	Sample
LM4040C41IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M43 ~ 4M4U)	Sample
LM4040C41IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P6U	Sample
LM4040C41IDCKRE4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P6U	Sample
LM4040C41IDCKRG4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P6U	Sample
LM4040C41ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC41I	Sample
LM4040C41ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC41I	Sample
LM4040C41ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC41I	Sample
LM4040C50IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NC3 ~ 4NCU)	Sample
LM4040C50IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NC3 ~ 4NCU)	Sample
LM4040C50IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NC3 ~ 4NCU)	Sample
LM4040C50IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NC3 ~ 4NCU)	Sample
LM4040C50IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MZU	Sample
LM4040C50ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC50I	Sample
LM4040C50ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC50I	Sample
LM4040C50ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC50I	Sample
LM4040C50QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NE3 ~ 4NEU)	Sample
LM4040C50QDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NE3 ~ 4NEU)	Sample



Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LM4040C50QDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NE3 ~ 4NEU)	Sample
LM4040C82IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NN3 ~ 4NNU)	Samples
LM4040C82IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PFU	Samples
LM4040C82ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC82I	Samples
LM4040C82ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFC82I	Samples
LM4040D20IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MV3 ~ 4MVU)	Samples
LM4040D20IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MV3 ~ 4MVU)	Samples
LM4040D20IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MV3 ~ 4MVU)	Samples
LM4040D20IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4MV3 ~ 4MVU)	Samples
LM4040D20IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MWU	Samples
LM4040D20IDCKRE4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MWU	Samples
LM4040D20IDCKRG4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MWU	Samples
LM4040D20ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD20I	Samples
LM4040D20ILPRE3	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD20I	Samples
LM4040D20QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MY3 ~ 4MYU)	Samples
LM4040D20QDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MY3 ~ 4MYU)	Samples
LM4040D20QDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MY3 ~ 4MYU)	Samples
LM4040D25IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ME3 ~ 4MEU)	Samples





Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Sample
LM4040D25IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ME3 ~ 4MEU)	Sample
LM4040D25IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ME3 ~ 4MEU)	Sample
LM4040D25IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ME3 ~ 4MEU)	Sample
LM4040D25IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MEU	Sample
LM4040D25IDCKRG4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MEU	Sample
LM4040D25IDCKT	ACTIVE	SC70	DCK	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MEU	Sample
LM4040D25IDCKTG4	ACTIVE	SC70	DCK	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	MEU	Sampl
LM4040D25ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD25I	Sampl
LM4040D25ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD25I	Sample
LM4040D25ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD25I	Sampl
LM4040D25QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MB3 ~ 4MBU)	Sampl
LM4040D25QDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MB3 ~ 4MBU)	Sampl
LM4040D25QDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MB3 ~ 4MBU)	Sampl
LM4040D25QDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4MB3 ~ 4MBU)	Sampl
LM4040D30IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M93 ~ 4M9U)	Sampl
LM4040D30IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M93 ~ 4M9U)	Sampl
LM4040D30IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M93 ~ 4M9U)	Sampl
LM4040D30IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M93 ~ 4M9U)	Sampl



Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LM4040D30IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PCU	Samples
LM4040D30IDCKT	PREVIEW	SC70	DCK	5	250	TBD	Call TI	Call TI	-40 to 85		
LM4040D30ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD30I	Samples
LM4040D30ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD30I	Samples
LM4040D30ILPM	PREVIEW	TO-92	LP	3	2000	TBD	Call TI	Call TI	-40 to 85		
LM4040D30ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD30I	Samples
LM4040D30ILPRE3	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD30I	Samples
LM4040D30QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NK3 ~ 4NKU)	Samples
LM4040D30QDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NK3 ~ 4NKU)	Samples
LM4040D41IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M53 ~ 4M5U)	Samples
LM4040D41IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M53 ~ 4M5U)	Samples
LM4040D41IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M53 ~ 4M5U)	Samples
LM4040D41IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4M53 ~ 4M5U)	Samples
LM4040D41IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	P7U	Samples
LM4040D41ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD41I	Samples
LM4040D41ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD41I	Samples
LM4040D41ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD41I	Samples
LM4040D41ILPRE3	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD41I	Samples
LM4040D50IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ND3 ~ 4NDU)	Samples





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Orderable Device	Status	Package Type	Package	Pins	_	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Sample
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
LM4040D50IDBZRG4	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ND3 ~ 4NDU)	Sample
LM4040D50IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ND3 ~ 4NDU)	Sample
LM4040D50IDBZTG4	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4ND3 ~ 4NDU)	Sample
LM4040D50IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	M4U	Sample
LM4040D50IDCKRG4	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	M4U	Sample
LM4040D50ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD50I	Sample
LM4040D50ILPE3	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD50I	Sample
LM4040D50ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD50I	Sample
LM4040D50ILPRE3	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD50I	Sample
LM4040D50QDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NF3 ~ 4NFU)	Sampl
LM4040D50QDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	(4NF3 ~ 4NFU)	Sampl
LM4040D82IDBZR	ACTIVE	SOT-23	DBZ	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NP3 ~ 4NPU)	Sampl
LM4040D82IDBZT	ACTIVE	SOT-23	DBZ	3	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	(4NP3 ~ 4NPU)	Sampl
LM4040D82IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	PGU	Sampl
LM4040D82ILP	ACTIVE	TO-92	LP	3	1000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD82I	Samp
LM4040D82ILPR	ACTIVE	TO-92	LP	3	2000	Pb-Free (RoHS)	CU SN	N / A for Pkg Type	-40 to 85	NFD82I	Samp

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.



#### PACKAGE OPTION ADDENDUM

7-Dec-2016

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

the die and leadframe. The component has a RohS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used by the die and leadframe. The component is otherwise considered Pb-Free (RohS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF LM4040C25:

Enhanced Product: LM4040C25-EP

NOTE: Qualified Version Definitions:

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

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### TAPE AND REEL INFORMATION



# TAPE DIMENSIONS KO P1 BO W Cavity AO

	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



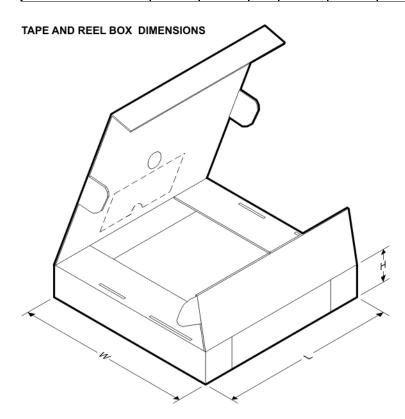
\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM4040A20IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040A25IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040A30IDBZT	SOT-23	DBZ	3	250	179.0	8.4	3.15	2.95	1.22	4.0	8.0	Q3
LM4040A30IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040A41IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040A50IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040A82IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040B10IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040B20IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040B25IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040B30IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040B41IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040B50IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040C10IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040C20IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040C20QDBZR	SOT-23	DBZ	3	3000	179.0	8.4	3.15	2.95	1.22	4.0	8.0	Q3
LM4040C20QDBZT	SOT-23	DBZ	3	250	179.0	8.4	3.15	2.95	1.22	4.0	8.0	Q3
LM4040C25IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3

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Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM4040C25IDCKT	SC70	DCK	5	250	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040C30IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040C41IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040C50IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040C82IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040D20IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040D20QDBZR	SOT-23	DBZ	3	3000	179.0	8.4	3.15	2.95	1.22	4.0	8.0	Q3
LM4040D20QDBZT	SOT-23	DBZ	3	250	179.0	8.4	3.15	2.95	1.22	4.0	8.0	Q3
LM4040D25IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040D25IDCKT	SC70	DCK	5	250	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040D30IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040D30QDBZR	SOT-23	DBZ	3	3000	179.0	8.4	3.15	2.95	1.22	4.0	8.0	Q3
LM4040D41IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040D50IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3
LM4040D82IDCKR	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM4040A20IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040A25IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0



## **PACKAGE MATERIALS INFORMATION**

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM4040A30IDBZT	SOT-23	DBZ	3	250	203.0	203.0	35.0
LM4040A30IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040A41IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040A50IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040A82IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040B10IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040B20IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040B25IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040B30IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040B41IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040B50IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040C10IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040C20IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040C20QDBZR	SOT-23	DBZ	3	3000	203.0	203.0	35.0
LM4040C20QDBZT	SOT-23	DBZ	3	250	203.0	203.0	35.0
LM4040C25IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040C25IDCKT	SC70	DCK	5	250	203.0	203.0	35.0
LM4040C30IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040C41IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040C50IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040C82IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040D20IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040D20QDBZR	SOT-23	DBZ	3	3000	203.0	203.0	35.0
LM4040D20QDBZT	SOT-23	DBZ	3	250	203.0	203.0	35.0
LM4040D25IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040D25IDCKT	SC70	DCK	5	250	203.0	203.0	35.0
LM4040D30IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040D30QDBZR	SOT-23	DBZ	3	3000	203.0	203.0	35.0
LM4040D41IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040D50IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0
LM4040D82IDCKR	SC70	DCK	5	3000	203.0	203.0	35.0

# DCK (R-PDSO-G5)

## PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
- D. Falls within JEDEC MO-203 variation AA.



# DCK (R-PDSO-G5)

## PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.





NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

Lead dimensions are not controlled within this area.

Falls within JEDEC TO−226 Variation AA (TO−226 replaces TO−92).

E. Shipping Method:

Straight lead option available in bulk pack only.

Formed lead option available in tape & reel or ammo pack.

Specific products can be offered in limited combinations of shipping mediums and lead options.

Consult product folder for more information on available options.





NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Tape and Reel information for the Formed Lead Option package.

# DBZ (R-PDSO-G3)

## PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Lead dimensions are inclusive of plating.
- D. Body dimensions are exclusive of mold flash and protrusion. Mold flash and protrusion not to exceed 0.25 per side.
- Falls within JEDEC TO-236 variation AB, except minimum foot length.



# DBZ (R-PDSO-G3)

## PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



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